

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant : Tohru Koike et al.  
Appl. No. : 10/575,714  
Filed : May 8, 2006  
For : METHOD FOR MEASURING A SURFACE PLASMON  
RESONANCE AND NOBLE METAL COMPOUND USED FOR THE  
SAME

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

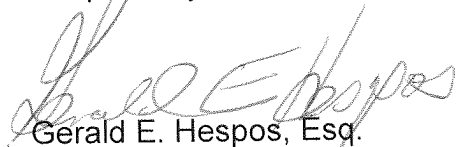
**SECOND INFORMATION DISCLOSURE STATEMENT**

Sir:

The above-identified U.S. patent application relates to Japanese Patent Appl. No. JP2006-077240. An Office Action was issued in connection with the Japanese application on October 6, 2009 and a copy of that Office Action is attached along with an English language translation. The Examiner will note that the Japanese Patent Office cited four non-patent publications and one Japanese reference. All of these references have been listed on the attached copy of Form PTO/SB/08A and copies of all the references are attached. The Japanese patent reference also is accompanied by an English language abstract obtained from the database of the Japanese Patent Office. Additionally, the Japanese language non-patent publication is accompanied by an English language translation.

The Examiner is requested to consider these references during the examination and to make the references of record.

Respectfully submitted,



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